

IN THE SPECIFICATION

Page 1, please replace the second paragraph with the following:

a2 Test systems wherein test vectors that are required for a test are stored in a large test vector memory are known to be used for the testing of logic components or logic switching circuits. Test vectors represent a number of logic patterns. In addition to such a test device there is an alternative which consists of [in] the integration of self-test units or BIST (Built In Self Test) units in the integrated circuits or ICs to be tested (Device Under Test or DUT). In the case of such BIST units the test vectors are generated in the DUT and the test response vectors are also processed in the DUT. The BIST units integrated in the DUT, however, take up an additional silicon surface area.

Page 1, please replace the fourth paragraph with the following:

a3 Types of faults that [necessitate] require a significantly larger number of test vectors are liable to occur in sub-micron processes. Such a larger number of test vectors, however, necessitates an even larger and more expensive test vector memory.